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- 1. A sapphire monocrystal body comprising a cleavage plane Parallel to a plane R of the crystal on the surface.
- 2. A sapphire monocrystal body according to claim 1, shale crystal wherein said monocrystal body is a sapphire tool comprising a sharp edge to be formed by the working plane and said cleavage plane.
- 3. A sapphire monocrystal body according to claim 1,
 Single crystal body is a monocrystal sapphire
 substrate comprising said cleavage plane on the side face.
 Single crystal
- 4. A sapphire monocrystal body according to claim 1, single crystal body has elements such as semiconductor element, functional element and the like on the major plane, and has said cleavage plane on the side face.
- 5. A monocrystal body according to claim 1, wherein single crystal single crystal sapphire substrate of a laser diode comprising a semiconductor multilayer for laser light emitting use formed on the major plane, and said cleavage plane connected with the cleaved plane of the multilayer on the side face.
- 6. A sapphire monderystal plate, wherein a working reference plane parallel or vertical to the plane R of the crystal is formed on the peripheral edge portion of said

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sapphire monocrystal plate, and the working reference plane makes an index for forming on the plate surface a microcrack line parallel to the plane R.

- 7. A sapphire monocrystal plate according to claim 6, wherein said working reference plane is in the angle range within ±10° from the orientation completely parallel or vertical to the plane R.
- 8. A sapphire monochystal plate according to claim 6, sapphire wherein said monosapphire crystal plate is a monocrystal sapphire substrate wherein elements such as semiconductor element, functional element or the like is to be formed on the major plane, and is to be formed said cleavage plane on the side face after the formation of the element.
- 9. A method of forming a cleavage plane of the single crystal sapphire memocrystal plate comprising forming microcrack line parallel to the plane R of the crystal on the plate single crystal plate, and subsequently giving mechanical or thermal stressing on the plate surface near the microcrack line, thereby growing the cracks and cleaving along the plane R.
- 10. A method of forming a cleavage plane according to claim 9, further comprising previously forming the reference plane parallel or vertical to the R plate of the crystal on the peripheral edge portion of said sapphire single crystal memocrystal plate, forming vertically or in parallel to the

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microcrack ine on the working reference plane in the formation of the cleavage plane.

- semiconductor multilayer for forming the laser element is Single Crystal provided on the major plane of the monocrystal sapphire substrate, two opposite reflection end faces comprising the resonator of the laser beam in the multilayer is a cleavage plane connected to the cleavage plane along the plane R of Single Crystal the crystal of said sapphire monocrystal substrate.
- 12. A semicondistor laser diode according to claim

 11, wherein said semiconductor multilayer is a multilayer

 of a gallium nitride system compound semiconductor of

 double hetero junction structure, the major plane of the

 Single Crustal

 monocrystal sapphire substrate is substantially parallel to

 the plane A, said cleavage plane of the substrate is

 comprised by 2.5 through 3.5° from the plane R of the

 sapphire crystal on the major plane and also is inclined in

 the direction from 59.5 through 60.5° from the plane C.
- 13. A method of manufacturing a semiconductor laser diode comprising forming semiconductor multilayer of the single crystal laser element on the major plane of the monocrystal sapphire substrate, then cleaving the monocrystal substrate and the multilayer along the plane R of the crystal, thereby making both the side cleavage planes of the

multilayer two opposite reflection end planes for composing the reasoner of the laser beam.

- diode comprising forming a semiconductor multilayer of the laser element on the major plane of the monocrystal sapphire substrate, then forming microcrack line parallel to the plane R of the crystal on the reverse plane of the sapphire monocrystal plane, subsequently giving mechanical or thermal stressing to the plate plane near the microcrack line, thereby growing the cracks and cleaving the single crystal substrate and the mutiplayer along the plane R, and making both the side cleavage planes of the multilayer two opposite reflection end faces for composing the reasoner of the laser beam.
- 15. A method of manufacturing of a semiconductor laser diode according to claim 14 further comprising forming the working reference plane parallel to or vertical to the plane R of the crystal on the peripheral edge Single Crystal portion on said monocrystal sapphire substrate in advance, thereby forming the microcrack line vertical or parallel to the reference plane when forming the cleavage plane.
- 16. A method of manufacturing a semiconductor laser diode comprising forming a multilayer of gallium nitride system compound semiconductor of double hetero junction structure of a laser element on the major plane of said

monocrystal sapphire substrate substantially parallel to the plane A by the major plane, then forming the microcrack line in a direction inclined by 2.5 through 3.5° from the plane R of the crystal and also inclined by 59.5 through 60.5° from the plane C on the reverse plane of said sapphire monocrystal plate, subsequently giving mechanical or thermal stressing to the plate plane near the microcrack line, thereby growing the cracks, cleaving the monocrystal substrate and the multilayer, and making both the cleaved planes of the multilayer two opposite reflection end faces for composing the resonator of the laser beam.

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